



PATENT
1152-0282P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Ren UCHIDA Conf.: 9224
Appl. No.: 09/941,683 Group: 2829
Filed: August 30, 2001 Examiner: PATEL, PARESH
For: TESTING METHOD AND TESTING DEVICE FOR
SEMICONDUCTOR INTEGRATED CIRCUITS

REPLY TO ELECTION OF SPECIES REQUIREMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

July 26, 2004

Sir:

In reply to the Election of Species Requirement dated June 25, 2004, the following remarks are respectfully submitted in connection with the above-identified application.

This reply includes: Remarks.

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If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to Deposit Account No. 02-2448 for any additional fees required under 37 C.F.R. § 1.16 or under 37 C.F.R. § 1.17; particularly, extension of time fees.

Respectfully submitted,

BIRCH, STEWART, KOLASCH & BIRCH, LLP

By 

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